PCN Number: 20190301000.1			4					PCN D	ate:	Mar 29 2019		
Title:	Title: Qualification of TI Chengdu A/T (CDAT) as an Assembly and test site for Select Device								Select Devices			
Custor	ner Conta	ct:	PCN A	Nanager		Dept: Quality Services						
Propos	sed 1 st Sh	in Da	ate:	June	4 20	019		Estimated				provided at
		.,,		34.10				Ava	<u>illat</u>	oility:	samp	le request
Chang	Change Type:											
	sembly Sit	e				Design				Wafe	r Bum	p Site
As	sembly Pro	cess				Data S	heet			Wafe	r Bum	p Material
	sembly Ma	terial	S			Part nu	ımber	change		Wafe	r Bum	p Process
Mechanical Specification			\boxtimes	Test Si	ite			Wafe	r Fab S	Site		
Packing/Shipping/Labeling T			Test Pr	ocess			Wafe	r Fab I	Materials			
						•	•			Wafe	r Fab I	Process
	PCN Details											

Description of Change:

Revision A is to announce the addition of new devices that were not included on the original PCN notification. Group 2 has additional devices and a new Group 4 has been created. These new devices are highlighted and **bolded** in the device list below. The expected first shipment date for these new devices will be 90 days from this notice for these newly added devices only.

Texas Instruments is pleased to announce the qualification of TI Chengdu (CDAT) as an Additional Assembly site for the list of devices shown below. Current assembly sites and Material differences are as follows:

Group 1 Devices:

	Clark	CDAT
Leadframe Prep	none	roughened
Mold compound	4208625	4222198
Mount Compound	4207768	4207123

Group 2 Devices:

	Clark	CDAT
Mold compound	4208625	4222198

Group 3 Devices:

_	Clark	UTAC	CDAT
Mold compound	4208625	SID#CZ0134	4222198
Mount compound	4207123	SID#PZ0031	4207123
Lead Finish	NiPdAu	NiPdAuAg	NiPdAu

Group 4 Devices:

	Clark	UTAC	CDAT
Mold compound	4208625	SID#CZ0289	4222198
Mount compound	4207123	SID#PZ0035	4207123
Lead Finish	NiPdAu	NiPdAuAg	NiPdAu

Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

Non	e						
Ant	Anticipated impact on Material Declaration						
	No Impact to the Material Declaration		Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained at the site link below http://www.ti.com/quality/docs/materialcontentsearch.tsp				

Changes to product identification resulting from this PCN:						
Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (21L)	Assembly City			
TI Clark	QAB	PHL	Angeles City, Pampang			
UTAC	NSE	THA	Bangkok			
CDAT	CDA	CHN	Chengdu			

Sample product shipping label (not actual product label)



MADE IN: Malaysia 2DC: 2Q: MSL '2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39

LBL: 5A (L)TO:39750



(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected:			
Group 1 Devices:	1	T	T
MSP430FR58671IRGZR	MSP430FR5868IRGZR	MSP430FR5967IRGZR	MSP430FR59691IRGZR
MSP430FR58671IRGZT	MSP430FR5868IRGZT	MSP430FR5967IRGZT	MSP430FR59691IRGZT
MSP430FR5867IRGZR	MSP430FR5869IRGZR	MSP430FR5968IRGZR	MSP430FR5969IRGZR
MSP430FR5867IRGZT	MSP430FR5869IRGZT	MSP430FR5968IRGZT	MSP430FR5969IRGZT
Group 2 Devices:			
TPS25740ARGER	TPS25740RGET	TPS25741RSMR	TPS51393RJET
TPS25740ARGET	TPS25741ARSMR	TPS25741RSMT	TPS51395RJER
TPS25740RGER	TPS25741ARSMT	TPS51393RJER	TPS51395RJET
Course 2 Design		•	
Group 3 Devices:	CC2F24F2FCDUAT	CC2F24PHAY	CC2544525CDUAD
CC2530F128RHAR	CC2531F256RHAT	CC2534RHAX	CC2541F256RHAR
CC2530F128RHAT	CC2533ARHAR	CC2540F128RHAR	CC2541F256RHAT
CC2530F12CRHA	CC2533CRHAR	CC2540F128RHAT	CC2541SRHAR
CC2530F256RHAR	CC2533F32RHAR	CC2540F256RHAR	CC2541SRHAT
CC2530F256RHAT	CC2533F32RHAT	CC2540F256RHAT	CC2570RHAR
CC2530F25CRHA	CC2533F64RHAR	CC2540F25ARHAR	CC2570RHAT
CC2530F32RHAR	CC2533F64RHAT	CC2540TF256RHAR	CC2571RHAR
CC2530F32RHAT	CC2533F96RHA	CC2540TF256RHAT	CC2571RHAT
CC2530F64RHAR	CC2533F96RHAR	CC2541CRHA	FRE008RHAR
CC2530F64RHAT	CC2533F96RHAT	CC2541CRHAR	FRE009RHAR
CC2531F128RHAR	CC2534RHA	CC2541F128RHAR	FRE010RHAR
CC2531F128RHAT	CC2534RHAR	CC2541F128RHAT	FRE015RHAR
CC2531F256RHAR	CC2534RHAT		
Group 4 Devices:			
CC1310F128RGZR	CC1310F64RSMR	CC2630F128RHBR	CC2640R2FRSMT
CC1310F128RGZT	CC1310F64RSMT	CC2630F128RHBT	CC2650F128RGZR
CC1310F128RHBR	CC1350F128RGZR	CC2630F128RSMR	CC2650F128RGZT
CC1310F128RHBT	CC1350F128RGZT	CC2630F128RSMT	CC2650F128RHBR
CC1310F128RSMR	CC1350F128RHBR	CC2640F128RGZR	CC2650F128RHBT
CC1310F128RSMT	CC1350F128RHBT	CC2640F128RGZT	CC2650F128RSMR
CC1310F32RGZR	CC1350F128RSMR	CC2640F128RHBR	CC2650F128RSMT
CC1310F32RGZT	CC1350F128RSMT	CC2640F128RHBT	CC2670F128RGZR
CC1310F32RHBR	CC2620F128RGZR	CC2640F128RSMR	CC2670F128RGZT
CC1310F32RHBT	CC2620F128RGZT	CC2640F128RSMT	CC2670F128RSMR
CC1310F32RSMR	CC2620F128RHBR	CC2640R2FRGZR	CC2670F128RSMT
CC1310F32RSMT	CC2620F128RHBT	CC2640R2FRGZT	FRE012RGZR
CC1310F64RGZR	CC2620F128RSMR	CC2640R2FRHBR	FRE012RHBR
CC1310F64RGZT	CC2620F128RSMT	CC2640R2FRHBT	FRE014RGZR

CC1310F64RHBR

CC1310F64RHBT

CC2630F128RGZR

CC2630F128RGZT

FRE014RHBR

CC2640R2FRSMR

Group 1 Devices Qual Memo:



TI Information
Selective Disclosure

Qualification Report

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: MSP430FR5969IRGZ	QBS Package Reference: <u>MSP430FR2633IRHB</u>
AC	Autoclave 121C	96 Hours	3/231/0	-
HAST	Biased HAST, 110C/85%RH	264 Hours	-	3/231/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	-
WBP	Bond Pull	Wires	3/228/0	-
WBS	Ball Bond Shear	Wires	3/228/0	-

⁻ QBS: Qualification By Similarity

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Group 2 Devices Qual Memos:

⁻ Qualification Device MSP430FR5969IRGZ is qualified at LEVEL2-260C

 $^{- \ \, \}text{Preconditioning was performed for Autoclave, Biased HAST, Temperature Cycle, and High Temp. Storage Bake.}$



Qualification Report

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TPS25725RSM	Qual Device: TPS25740ARGE	Qual Device: TPS25740RGE	Qual Device: TPS25741ARSM	Qual Device: TPS25741RSM	QBS Package Reference: TPS2231RGPR
AC	Autoclave 121C	96 Hours	-	-	-	-	-	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	-	-	Pass	-	Pass	-
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	-	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	-	-	-
HBM	ESD - HBM	3000 V	-	1/3/0	-	-	-	-
CDM	ESD - CDM	1000 V	1/3/0	1/3/0	-	-	1/3/0	-
HTOL	Life Test, 125C	1000 Hours	-	-	-	-	-	-
HTOL	Life Test, 140C	480 Hours	-	-	-	-	-	-
HTOL	Life Test, 150C	300 Hours	-	-	-	-	-	-
HTOL	Life Test, 155C	240 Hours	-	-	-	-	-	3/231/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	-	-	-	3/231/0
HTSL	High Temp. Storage Bake, 150C	500 Hours	-	-	-	-	-	-
LU	Latch-up	(per JESD78)	-	1/6/0	-	-	1/6/0	-
PD	Physical Dimensions		-	-	-	-	-	3/15/0
SD	Solderability	8 Hours Steam Age	-	-	-	-	-	3/66/0
TC	Temperature Cycle, -55/125C	700 Cycles	-	-	-	-	-	-
TC	Temperature Cycle, -65/150C	500 Cycles	-	-	-	-	-	3/231/0
TS	Thermal Shock -65/150C	500 Cycles	-	-	-	-	-	3/231/0
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-	-	-	-	-	-
WBP	Bond Pull	Wires	-	-	-	-	-	3/228/0
WBS	Bond Shear	Wires	-	-	-	-	-	3/228/0
YLD	FTY and Bin Summary		Pass	Pass	Pass	Pass	Pass	-

⁻ QBS: Qual By Similarity

- QBS: Qual By Similarity
 Qual Devices qualified at LEVEL2-260CG: TPS25740RGE, TPS25741RSM, TPS25725RSM, TPS25740ARGE, TPS25741ARSM
 Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
 The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
 The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles
 Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green



TI Information Selective Disclosure

Qualification Report

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TPS51395RJE	Qual Device: TP\$51393RJE	QBS Product Reference: <u>TPS51393RJE</u>	QBS Product Reference: <u>TPS51393RJE</u>
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	-
HBM	ESD - HBM	2500 V	-	3/9/0	3/9/0	-
CDM	ESD - CDM	1500 V	-	3/9/0	3/9/0	-
LU	Latch-up	(per JESD78)	-	3/18/0	3/18/0	-
HTOL	Life Test, 125C	1000 Hours	-	3/231/0	3/230/0	1/77/0
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	-	3/2400/0
HTSL	High Temp Storage Bake, 170C	420 Hours	-	3/231/0	3/231/0	1/77/0
HAST	Biased HAST, 110C/85%RH	264 Hours	-	-	1/77/0	3/231/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-	-
UHAST	Unbiased HAST, 110C/85%RH	264 Hours	-	-	-	3/231/0
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-	3/231/0		
AC	Autoclave, 121C/100%RH	96 Hours	-	-	1/77/0	-
TC	Temperature Cycle, -55/125C	700 Cycles	-	3/231/0	1/77/0	3/231/0
SD	Surface Mount Solderability	Pb Free	-	3/66/0	-	
SD	Surface Mount Solderability	Pb	-	3/66/0	-	-
PD	Physical Dimensions	-	-	3/90/0	-	-

- QBS: Qual By Similarity
 Qual Device TPS51393RJE is qualified at LEVEL2-260C
 Qual Device TPS51395RJE is qualified at LEVEL2-260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/14k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
 The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
 The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles
 The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

Group 3 Devices Qual Memo:



Qualification Report

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: CC2540F256RHAR	QBS Package Reference: <u>MSP430F5172IRSBR</u>
AC	Autoclave 121C	96 Hours	1/77/0	3/231/0
HAST	Biased HAST, 110C/85%RH	264 Hours	-	3/77/0
HTSL	High Temp Storage Bake 150C	1000 Hours	-	3/231/0
TC	Temperature Cycle, -55/125C	700 Cycles	1/77/0	-
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0

- QBS: Qual By Similarity
- Qual Device CC2540F256RHAR is qualified at LEVEL3-260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Group 4 Devices Qual Memo:



TI Information
Selective Disclosure

Qualification Report

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: CC2640R2FRGZR	Qual Device: CC2640R2FRSMR
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hours	3/231/0	-
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	3/231/0
THB	Biased Temperature and Humidity, 85C/85%RH	1000 Hours	3/78/0	-

- QBS: Qual By Similarity
- Qual Device CC2640R2FRSMR is qualified at LEVEL3-260CG
- Qual Device CC2640R2FRGZR is qualified at LEVEL3-260CG
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

Location	E-Mail		
USA	PCNAmericasContact@list.ti.com		
Europe	PCNEuropeContact@list.ti.com		
Asia Pacific	PCNAsiaContact@list.ti.com		
WW PCN Team	PCN www admin_team@list.ti.com		